

### Description

The AOD21357 uses advanced trench technology

to provide excellent  $R_{\text{DS}(\text{ON})}\text{,}$  low gate charge and

operation with gate voltages as low as 4.5V. This

device is suitable for use as a

Battery protection or in other Switching application.

### **General Features**

V<sub>DS</sub> = -30V I<sub>D</sub> =80 A

 $R_{DS(ON)} < 8.8 \, m\Omega @ V_{GS} = 10V$ 

## Application

Battery protection

Load switch Uninterruptible power supply

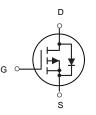
#### Package Marking and Ordering Information

Product ID	Pack	Brand	Qty(PCS)
AOD21357	TO-252-2L	HXY MOSFET	2500

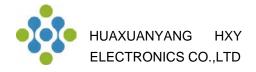
#### Absolute Maximum Ratings (Tc=25°Cunless otherwise noted)

Symbol	Parameter	Rating	Units	
Vds	Drain-Source Voltage	-30	V	
Vgs	Gate-Source Voltage	±25	V	
I <sub>D</sub> @T <sub>C</sub> =25°C	Continuous Drain Current, V <sub>GS</sub> @ -10V <sup>1</sup>	-80	А	
I⊳@Tc=100°C	Continuous Drain Current, V <sub>GS</sub> @ -10V <sup>1</sup>	-42	А	
Ідм	Pulsed Drain Current <sup>2</sup>	-172	А	
EAS	Single Pulse Avalanche Energy <sup>3</sup>	31	mJ	
las	Avalanche Current	-25	А	
P <sub>D</sub> @T <sub>C</sub> =25°C	Total Power Dissipation <sup>4</sup>	31.2	W	
P <sub>D</sub> @T <sub>A</sub> =25°C	Total Power Dissipation <sup>4</sup>	2	W	
Тѕтс	Storage Temperature Range	-55 to 150	°C	
TJ	Operating Junction Temperature Range	-55 to 150	°C	
R <sub>0JA</sub>	Thermal Resistance Junction-Ambient <sup>1</sup>	43	°C/W	
Rejc	Thermal Resistance Junction-Case <sup>1</sup>	4	°C/W	





P-Channel MOSFET



## Electrical Characteristics T<sub>c</sub> = 25°C, unless otherwise noted

Parameter		Symbol	Test Conditions	Min.	Тур.	Max.	Unit	
Drain-Source Breakdown Voltage		V <sub>(BR)DSS</sub>	V <sub>GS</sub> = 0V, I <sub>D</sub> = -250µA	-30	-	-	V	
Gate-body Leakage current		I <sub>GSS</sub>	$V_{DS} = 0V, V_{GS} = \pm 20V$	-	-	±100	nA	
Zero Gate Voltage Drain	TJ=25℃		V <sub>DS</sub> = -24V, V <sub>GS</sub> = 0V	-	-	-1	μA	
Current	TJ=55℃	- I <sub>DSS</sub>	$v_{\rm DS} = -24 v, v_{\rm GS} = 0 v$	-	-	-5		
Gate-Threshold Voltage		V <sub>GS(th)</sub>	$V_{DS}$ = $V_{GS}$ , $I_D$ = -250 $\mu$ A	-1.0	-1.6	-2.5	V	
Drain Source On Desistens	o <sup>2</sup>	_	V <sub>GS</sub> = -10V, I <sub>D</sub> = -12A	-	5.5	8.8		
Drain-Source On-Resistance <sup>2</sup>		R <sub>DS(on)</sub>	V <sub>GS</sub> = -4.5V, I <sub>D</sub> = -8A	- 9		14	- mΩ	
Forward Transconductance		<b>g</b> fs	V <sub>DS</sub> = -5V, I <sub>D</sub> = -20A	-	28	-	S	
Input Capacitance		Ciss	V <sub>DS</sub> = -15V, V <sub>GS</sub> =0V, f =1MHz	-	4320	-	pF	
Output Capacitance		Coss		-	529	-		
Reverse Transfer Capacitance		C <sub>rss</sub>		-	487	-		
Gate Resistance		R <sub>g</sub>	$V_{DS}$ = 0V, $V_{GS}$ = 0V, f=1.0MHz	-	4.0	-	Ω	
Total Gate Charge		Qg		-	45	-	nC	
Gate-Source Charge		Q <sub>gs</sub>	V <sub>GS</sub> = -10V, V <sub>DS</sub> = -15V, I <sub>D</sub> = -15A	-	8.5	-		
Gate-Drain Charge		Q <sub>gd</sub>		-	12.8	-		
Turn-On Delay Time		td(on)		-	18.9	-	. nS	
Rise Time		tr	V <sub>GS</sub> = -10V, V <sub>DD</sub> = -15V,	-	15.7	-		
Turn-Off Delay Time		td(off)	R <sub>G</sub> = 2.5Ω, I <sub>D</sub> = -15A	-	64.8	-		
Fall Time		tr		-	36.5	-		
Diode Forward Voltage <sup>2</sup>		Vsd	I <sub>S</sub> = -1A, V <sub>GS</sub> = 0V	-	-	-1	V	
Continuous Source Current <sup>1,5</sup>		ls	Vg=VD=0V , Force Current	-	-	-80	А	

Note :

1. The data tested by surface mounted on a 1 inch<sup>2</sup> FR-4 board with 2OZ copper.

2.The data tested by pulsed , pulse width  $\leq$  300us , duty cycle  $\leq 2\%$ 

3. The EAS data shows Max. rating . The test condition is V\_DD= -25V, V\_GS= -10V, L= 0.1mH, I\_{AS}= -25A

4.The power dissipation is limited by  $150^{\circ}$ C junction temperature

5. The data is theoretically the same as  $I_{\text{D}}$  and  $I_{\text{DM}}$  , in real applications , should be limited by total power dissipation.



#### **Typical Characteristics**

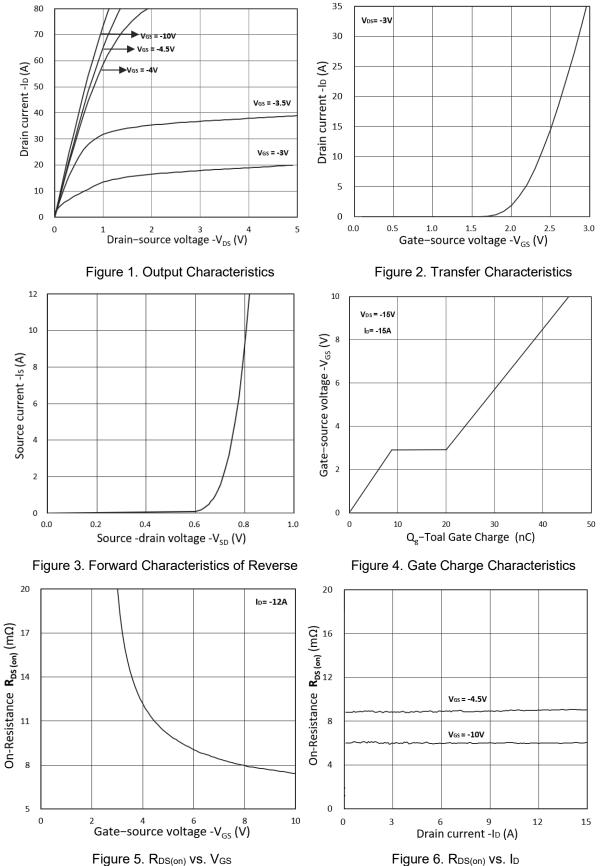


Figure 5. RDS(on) vs. VGS



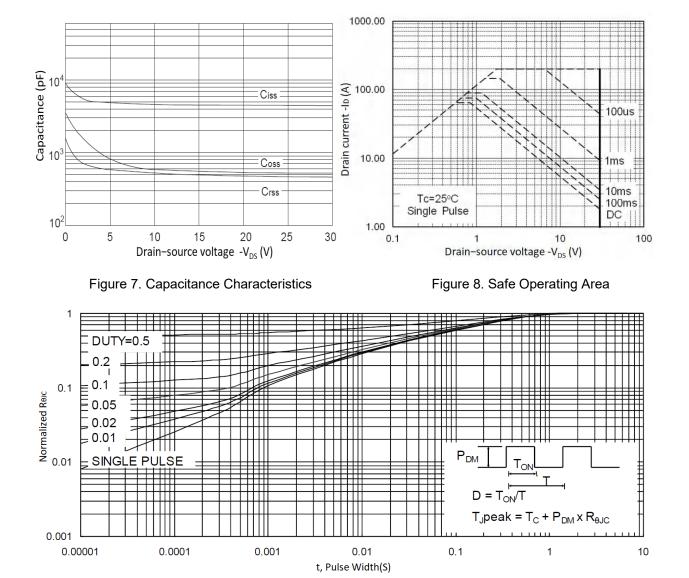


Figure 9. Normalized Maximum Transient Thermal Impedance

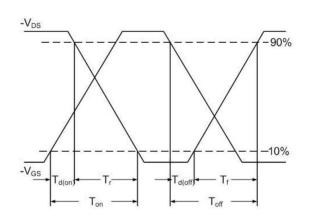
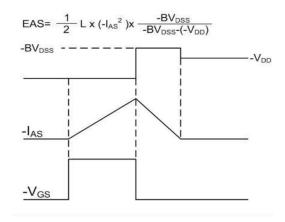
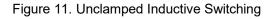
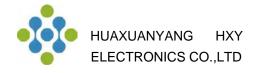


Figure 10. Switching Time Waveform

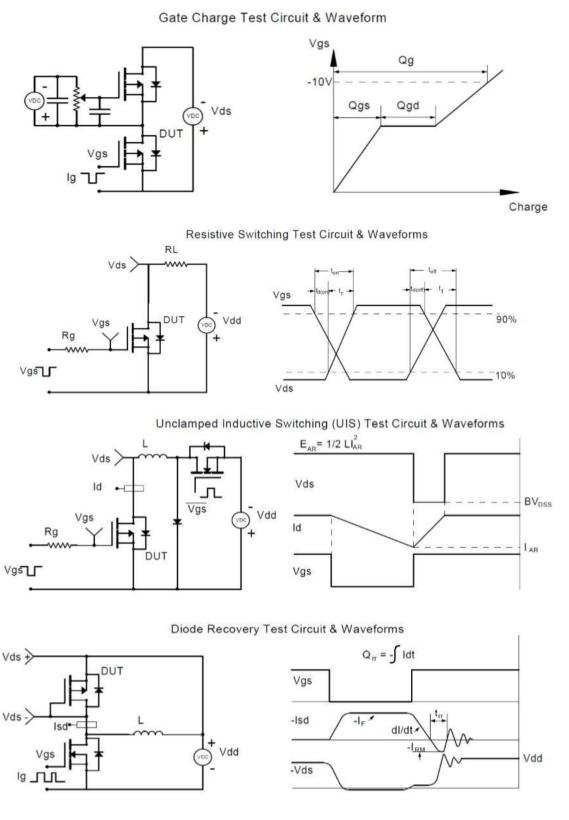


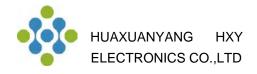


Waveform

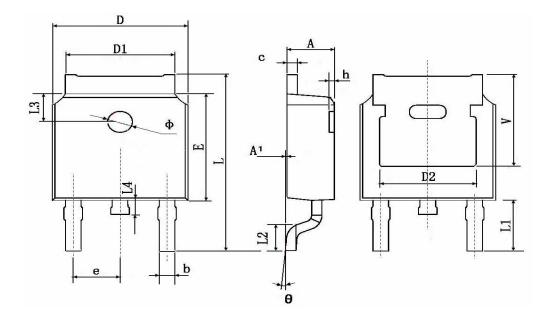


# **Test Circuit**





# TO-252-2L Package Information



Symbol	Dimensions In Millimeters		Dimensions In Inches		
	Min.	Max.	Min.	Max.	
A	2.200	2.400	0.087	0.094	
A1	0.000	0.127	0.000	0.005	
b	0.660	0.860	0.026	0.034	
С	0.460	0.580	0.018	0.023	
D	6.500	6.700	0.256	0.264	
D1	5.100	5.460	0.201	0.215	
D2	4.830 TYP.		0.190 TYP.		
E	6.000	6.200	0.236	0.244	
е	2.186	2.386	0.086	0.094	
L	9.800	10.400	0.386	0.409	
L1	2.900 TYP.		0.114 TYP.		
L2	1.400	1.700	0.055	0.067	
L3	1.600	1.600 TYP.		0.063 TYP.	
L4	0.600	1.000	0.024	0.039	
Φ	1.100	1.300	0.043	0.051	
θ	0 °	8°	0°	8°	
h	0.000	0.300	0.000	0.012	
V	5.350 TYP.		0.211 TYP.		



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